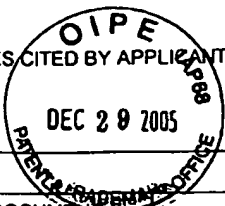


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249958US2S DIV		SERIAL NO. 10/802,784	
<div style="display: flex; align-items: center; justify-content: center;"> <div style="text-align: center;">  <p>LIST OF REFERENCES CITED BY APPLICANT</p> </div> </div>				APPLICANT Koji MARUYAMA, et al.			
				FILING DATE March 18, 2004		GROUP 2615 2621	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
	AO	9-63252	03/07/1997	JAPAN		X	
	AP	8-18923	01/19/1996	JAPAN		X	
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner		Date Considered					
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

3/18/04

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249958US2S DIV		SERIAL NO. New DIV Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Koji MARUYAMA, et al.			
				FILING DATE HEREWITH		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>DM</i>	AA	6,148,138	11/14/2000	Sawabe et al.			
<i>DM</i>	AB	5,546,191	11/19/1996	Hibi et al.			
<i>DM</i>	AC	5,576,950	11/19/1996	Tonomura et al.			
<i>DM</i>	AD	6,006,007	12/21/1999	Honjo			
<i>DM</i>	AE	5,819,004	10/1998	Azadegan et al.			
<i>DM</i>	AF	5,701,385	12/1997	Katsuyama et al.			
<i>DM</i>	AG	5,966,352	10/1999	Sawabe et al.			
<i>DM</i>	AH	6,424,793	07/2002	Setogawa et al.			
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>DM</i>	AO	3-183091	8/9/91	Japan			X
<i>DM</i>	AP	7-250300	09/26/1995	Japan	x		
<i>DM</i>	AQ	9-259573	10/03/97	Japan (corresponds to U.S. Pat. No. 5,966,352)			x
<i>DM</i>	AR	64-066839	03/13/1989	Japan (English Abstract Only)			x
<i>DM</i>	AS	3-183091	08/09/1991	Japan (English Abstract Only)			x
<i>DM</i>	AT	8-111843	04/1996	Japan			
<i>DM</i>	AU	8-163507	06/1996	Japan			
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>DM</i>	AW	Explanation of Circumstances Concerning Accelerated Examination: AD 90202744 (for Japanese Patent Application No. 2002-158118)					
<i>DM</i>	AX	Explanation of Circumstances Concerning Accelerated Examination: AD 09800092 (for Japanese Patent Application No. 1998-009983)					
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>DM</i>					Date Considered <i>8/3/06</i>		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							